Device Modeling Report

COMPONENTS: BIPOLAR JUNCTION TRANSISTOR PART NUMBER: 2SA1162(Y) MANUFACTURER: TOSHIBA



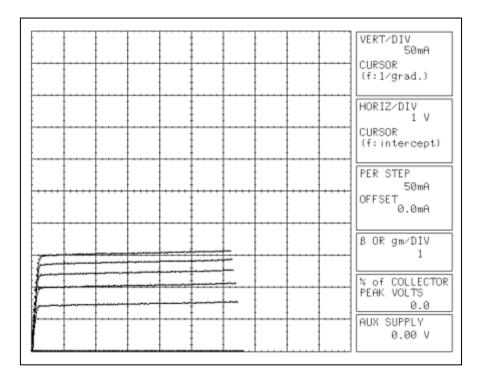
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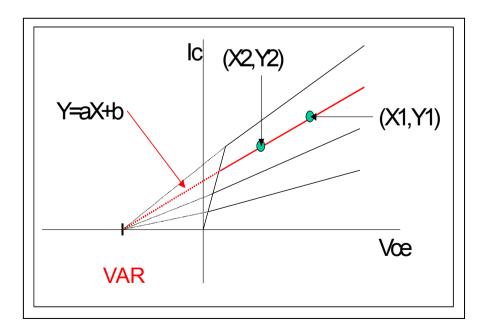
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PSpice model	Model description		
parameter			
IS	Saturation Current		
BF	Ideal Maximum Forward Beta		
NF	Forward Current Emission Coefficient		
VAF	Forward Early Voltage		
IKF	Forward Beta Roll-off Knee Current		
ISE	Non-ideal Base-Emitter Diode Saturation Current		
NE	Non-ideal Base-Emitter Diode Emission Coefficient		
BR	Ideal Maximum Reverse Beta		
NR	Reverse Emission Coefficient		
VAR	Reverse Early Voltage		
IKR	Reverse Beta Roll-off Knee Current		
ISC	Non-ideal Base-Collector Diode Saturation Current		
NC	Non-ideal Base-Collector Diode Emission Coefficient		
NK	Forward Beta Roll-off Slope Exponent		
RE	Emitter Resistance		
RB	Base Resistance		
RC	Series Collector Resistance		
CJE	Zero-bias Emitter-Base Junction Capacitance		
VJE	Emitter-Base Junction Potential		
MJE	Emitter-Base Junction Grading Coefficient		
CJC	Zero-bias Collector-Base Junction Capacitance		
VJC	Collector-base Junction Potential		
MJC	Collector-base Junction Grading Coefficient		
FC	Coefficient for Onset of Forward-bias Depletion		
	Capacitance		
TF	Forward Transit Time		
XTF	Coefficient for TF Dependency on Vce		
VTF	Voltage for TF Dependency on Vce		
ITF	Current for TF Dependency on Ic		
PTF	Excess Phase at f=1/2pi*TF		
TR	Reverse Transit Time		
EG	Activation Energy		
XTB	Forward Beta Temperature Coefficient		
XTI	Temperature Coefficient for IS		

Reverse

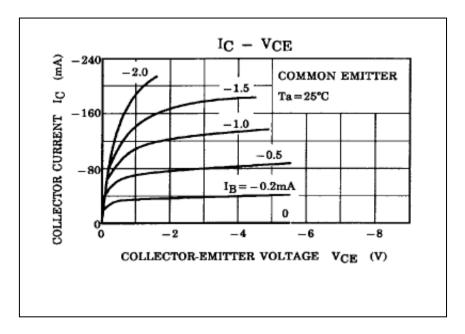
Reverse Early Voltage Characteristic

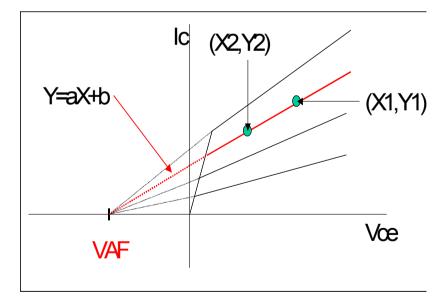




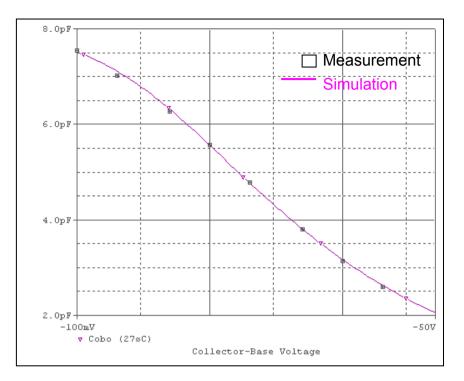
Forward

Forward Early Voltage Characteristic

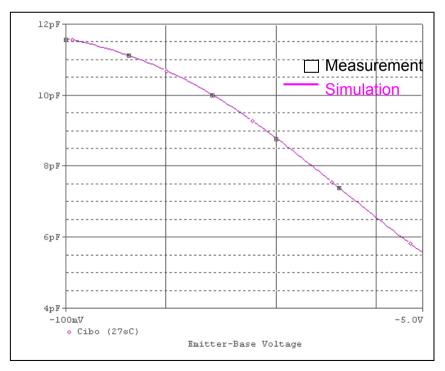




C-B Capacitance Characteristic

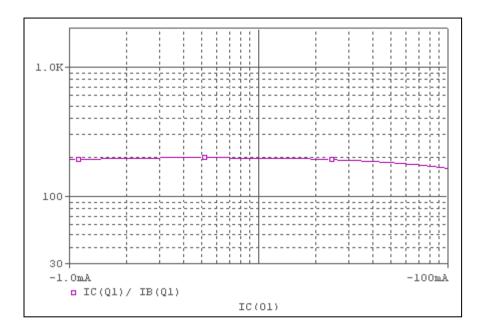


E-B Capacitance Characteristic

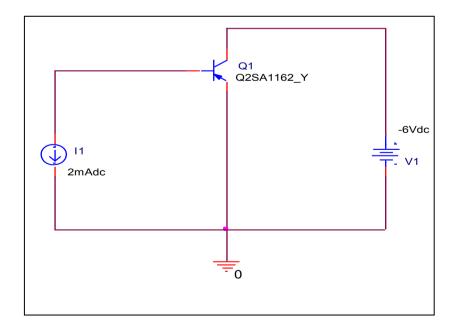


BJT Ic-hFE Characteristics

Circuit simulation result



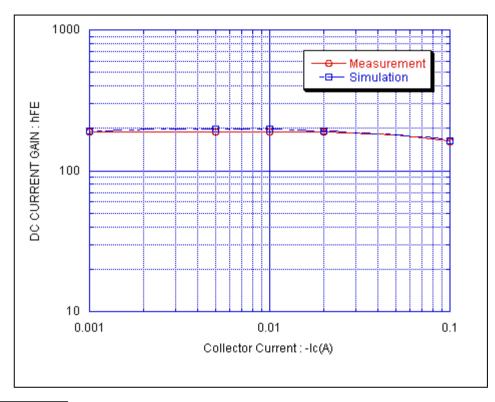
Evaluation circuit



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Comparison Graph

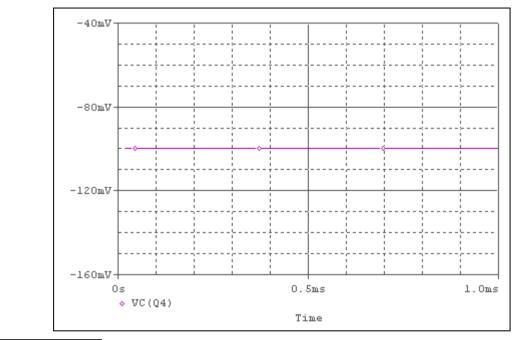
Circuit simulation result



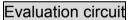
Simulation result

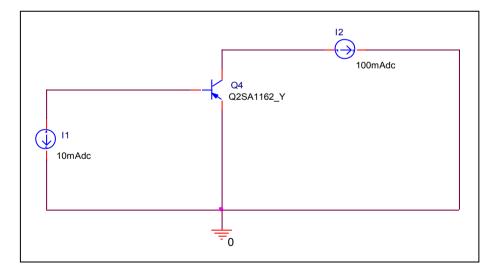
lc(A)		hfe	
	measurement	simulate	%Error
-0.001	190	192	1.052
-0.002	190	197	3.684
-0.005	190	198	4.210
-0.01	190	197	3.684
-0.02	190	193	1.578
-0.05	180	181	0.555
-0.1	160	162	1.25

BJT Vce (sat) voltage & VBe (sat) voltage Characteristics



Circuit simulation result





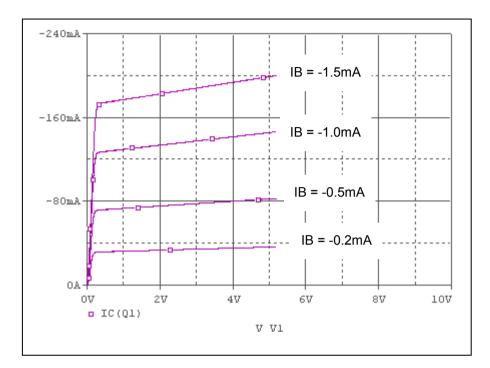
Simulation result

Test condition: IC/IB = 10, IC=-100mA

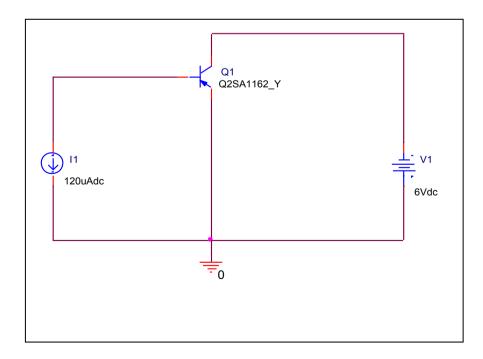
	Measurement	Simulation	%Error
Vce(sat)(A)	-100m	-97.483m	-2.517
Vbe(sat)(A)	-900m	-902.154m	0.238

Output Characteristics

Circuit simulation result



Evaluation circuit



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